INFORMATION DISCLOSURE STATEMENT

Applicants

Gonzalez, et al.

App. No.

Unknown

Filed

Herewith

For

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CONSTRUCTION

Examiner

Unknown

Group Art Unit

Unknown

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Enclosed are copies of forms PTO-1449 and 892 listing 31 references. These references are of record on related application No. 09/879,604, filed June 12, 2001. Therefore, copies of the references are not enclosed. This Information Disclosure Statement is being submitted upon filing, and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1).

Identification herein is not an admission that any of the foregoing references are prior art to the above-captioned application.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: Sept. 12,2003

Michael S. Okamoto

Registration No. 47,831

Attorney of Record

Customer No. 20,995

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	S. Shimizu, et al., "Impact of Surface Proximity Gettering and Nitrided Oxide Side-Wall Spacer by Nitrogen Implantation on Sub-Quarter Micron CMOS LDD FETs," IEDM 1995, pp. 859-862								

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Applicant(s)/Patent Under Application/Control No. Reexamination 09/879,004 UNKROWN GONZALEZ ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Kevin Quinto 2826-**U.S. PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date Name Classification MM-YYYY 03-1992 US-5,101,251 Wakamiya et al. US-5,395,786 В 03-1995 Hsu et al. US-С D US-US-Ε US-F US-G US-Н US-1 US-J κ US-US-L US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY N 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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